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- Meet or Exceed the Requirements of ANSI EIA/TIA-422-B and ITU Recommendation V.11
- Low Power, I_{CC} = 100 μA Typ
- Operate From a Single 5-V Supply
- High Speed, t_{PLH} = t_{PHL} = 7 ns Typ
- Low Pulse Distortion, t_{sk(p)} = 0.5 ns Typ
- High Output Impedance in Power-Off Conditions
- Improved Replacement for AM26LS31

description

The AM26C31C, AM26C31I, and AM26C31M are four complementary-output line drivers designed to meet the requirements of ANSI EIA/TIA-422-B and ITU (formerly CCITT). The 3-state outputs have high-current capability for driving balanced lines such as twisted-pair or parallel-wire transmission lines, and they provide the high-impedance state in the power-off condition. The enable function is common to all four drivers and offers the choice of an active-high or active-low enable input. BiCMOS circuitry reduces power consumption without sacrificing speed.

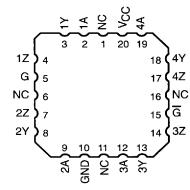
The AM26C31C is characterized for operation from 0°C to 70°C, the AM26C31I is characterized for operation from -40°C to 85°C, and the AM26C31M is characterized for operation from -55°C to 125°C

AM26C31C, AM26C31I . . . D OR DBT OR N PACKAGE AM26C31M . . . J OR W PACKAGE (TOP VIEW)

1A [1Y [1Z [2Z [2Y [1 2 3 4 5 6 7	O	15 14 13 12 11] 3Z
2A [GND [7 8		10 9	32 3Y 3A

†The DB package is only available left-ended taped (order AM26C31IDBLE or AM26C31CDBLE).

AM26C31M . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

FUNCTION TABLE (each driver)

INPUT	ENA	BLES	OUTPUTS		
Α	G	G	Y	Z	
Н	Н	Х	Н	L	
L	Н	Х	L	Н	
Н	X	L	н	L	
L	X	L	L	Н	
Х	L	Н	Z	Ζ	

H = high level

X = irrelevant

L = low level

Z = high impedance (off)



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



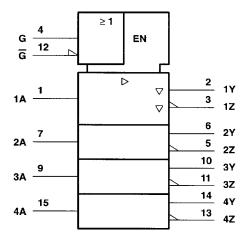
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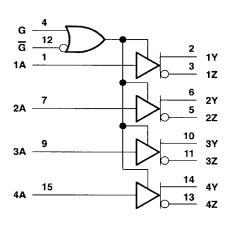
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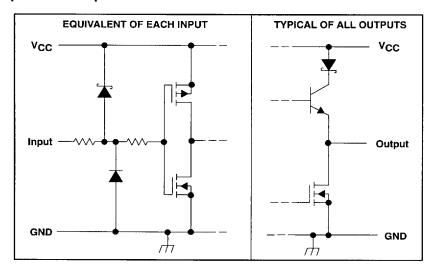
logic symbol† logic diagram (positive logic)





NOTE A: The terminal numbers shown are for the D, DB, J, and W packages.

schematics of inputs and outputs



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC} (see Note 1)	0.5 V to 7 V
Input voltage range, V _I	\dots -0.5 V to V _{CC} + 0.5 V
Differential input voltage range, V _{ID}	
Output voltage range, VO	$\dots \dots $
Input or output clamp current, IIK or IOK	±20 mA
Output current, IO	±150 mA
V _{CC} current	200 mA
GND current	–200 mA
Continuous total power dissipation	See Dissipation Rating Table
Storage temperature range, T _{sto}	65 C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values, except differential output voltage (VOD), are with respect to the network ground terminal.

DISSIPATION RATING TABLE

PACKAGE	T _A ≤ 25°C POWER RATING	DERATING FACTOR ABOVE T _A = 25°C	T _A = 70°C POWER RATING	T _A = 85°C POWER RATING	T _A = 125°C POWER RATING
D	950 mW	7.6 mW/°C	608 mW	494 mW	_
DB	781 mW	6.2 mW/°C	502 mW	409 mW	_
N	1150 mW	9.2 mW/°C	736 mW	598 mW	- .
FK	1375 mW	11 mW/°C	_		275 mW
J	1375 mW	11 mW/°C	_	_	275 mW
w	1000 mW	8.0 mW/°C	_	_	200 mW

recommended operating conditions

		 MIN	NOM	MAX	UNIT
Supply voltage, V _{CC}		4.5	5	5.5	٧
Differential input voltage, V _{ID}			±7		>
High-level input voltage, VIH		2			٧
Low-level input voltage, V _{IL}				0.8	٧
High-level output current, IOH				-20	mA
Low-level output current, IOL				20	mA
	AM26C31C	0		70	
Operating free-air temperature, TA	AM26C31I	-40		85	°C
	AM26C31M	-55		125	



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electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS		AM26C31C AM26C31I			UNIT
				MIN	TYPT	MAX	
VOH	High-level output voltage	I _O = -20 mA		2.4	3.4		V
v_{OL}	Low-level output voltage	I _O = 20 mA			0.2	0.4	V
IVODI	Differential output voltage magnitude			2	3.1		V
ΔIV _{OD} I	Change in magnitude of differential output voltage‡					±0.4	٧
Voc	Common-mode output voltage	$R_L = 100 \Omega$,	See Figure 1			3	V
ΔIVOCI	Change in magnitude of common-mode output voltage‡	1				±0.4	٧
lį	Input current	$V_I = V_{CC}$ or (GND			±1	μA
la cm	Driver output current with power off	$V_{CC} = 0$,	V _O = 6 V		_	100	
IO(off)		V _{CC} = 0,	V _O = -0.25 V			100	μΑ
los	Driver output short-circuit current	V _O = 0		-30		- 150	mA
1	Link impodence off state output assumed	V _O = 2.5 V				20	μΑ
loz	High-impedance off-state output current	V _O = 0.5 V				-20	μΑ
		I _O = 0,	V ₁ = 0 V or 5 V			100	μΑ
ICC	Quiescent supply current	I _O = 0, See Note 2	V _I = 2.4 V or 0.5 V,		1.5	3	mA
CI	Input capacitance				6		pF

[†] All typical values are at $V_{CC} = 5 \text{ V}$ and $T_A = 25^{\circ}\text{C}$.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST CO	TEST CONDITIONS		AM26C31C AM26C31I		
					TYP	MAX	UNIT
^t PLH	Propagation delay time, low- to high-level output			5.7	7	12	ns
^t PHL	Propagation delay time, high- to low-level output	S1 is open,	See Figure 2	5.4	7	12	ns
tsk(p)	Pulse skew time (ItpLH - tpHLI)	7		0.5	4	ns	
tr(OD), tf(OD)	Differential output rise and fall times	S1 is open,	See Figure 3		5	10	ns
^t PZH	Output enable time to high level				10	19	ns
^t PZL	Output enable time to low level	7	0 5		10	19	ns
^t PHZ	Output disable time from high level	S1 is closed,	See Figure 4		7	16	ns
^t PLZ	Output disable time from low level	7			7	16	ns
C _{pd}	Power dissipation capacitance (each driver) (see Note 3)	S1 is open,	See Figure 2		170		pF

[†] All typical values are at $V_{CC} = 5$ V and $T_A = 25$ °C.



[‡] ΔIVODI and ΔIVOCI are the changes in magnitude of VOD and VOC, respectively, that occur when the input is changed from a high level to a low level.

NOTE 2: This parameter is measured per input. All other inputs are at 0 or 5 V.

NOTE 3: Cpd is used to estimate the switching losses according to Pp = Cpd VCC² f, where f is the switching frequency.

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electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER		TEST CONDITIONS		AM26C31M			
ļ	PARAMETER		1231 CONDITIONS		MIN	TYPT	MAX	TINU
VOH	High-level output voltage	$I_{O} = -20 \text{ mA}$			2.2	3.4		٧
VOL	Low-level output voltage	IO = 20 mA				0.2	0.4	٧
IV _{OD} I	Differential output voltage magnitude				2	3.1		٧
ΔIV _{OD} I	Change in magnitude of differential output voltage‡	D 400 C	0 5: 1		:		±0.4	٧
Voc	Common-mode output voltage	R_L = 100 Ω, See Figure 1					3	٧
ΔIVOCI	Change in magnitude of common-mode output voltage‡						±0.4	٧
l I _I	Input current	V _I = V _{CC} or 0	V _I = V _{CC} or GND				±1	μА
la (m	Driver output current with power off	$V_{CC} = 0$,	V _O = 6 V				100	^
^I O(off)	Driver datput current with power on	$V_{CC} = 0$,	V _O = −0.25 V				-100	μА
los	Driver output short-circuit current	V _O = 0					-170	mA
lon	High-impedance off-state output current	$V_0 = 2.5 \text{ V}$					20	μΑ
loz	High-impedance oil-state output current	V _O = 0.5 V					-20	μΑ
laa	Quiescent august ourrent	l _O = 0,	$V_I = 0 V \text{ or } 5 V$				100	μΑ
Icc	Quiescent supply current	IO = 0,	$V_I = 2.4 \text{ V or } 0.5 \text{ V},$	See Note 2			3.2	mA
CI	Input capacitance					6		pF

[†] All typical values are at $V_{CC} = 5 \text{ V}$ and $T_A = 25^{\circ}\text{C}$.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST C	TEST CONDITIONS		AM26C31M		
	PANAMETER	TEST CO	DINDITIONS	MIN	TYP†	MAX	UNIT
tPLH	Propagation delay time, low- to high-level output				7	12	ns
tPHL	Propagation delay time, high- to low-level output	S1 is open,	See Figure 2		6.5	12	ns
t _{sk(p)}	Pulse skew time (ItpLH - tpHLI)	7			0.5	4	ns
tr(OD), tf(OD)	Differential output rise and fall times	S1 is open,	See Figure 3		5	12	ns
^t PZH	Output enable time to high level				10	19	ns
tPZL	Output enable time to low level	S1 is closed,	See Figure 4		10	19	ns
^t PHZ	Output disable time from high level	31 is closed,	See Figure 4		7	16	ns
^t PLZ	Output disable time from low level				7	16	ns
C _{pd}	Power dissipation capacitance (each driver) (see Note 3)	S1 is open,	See Figure 2		100		pF

† All typical values are at V_{CC} = 5 V and T_A = 25°C. NOTE 3: C_{pd} is used to estimate the switching losses according to $P_D = C_{pd} \times V_{CC}^2$ f, where f is the switching frequency.



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^{\$\(\}delta\IV_{OD}\) and \(\Delta\IV_{OC}\) are the changes in magnitude of V_{OD} and V_{OC}, respectively, that occur when the input is changed from a high level to a low level.

NOTE 2: This parameter is measured per input. All other inputs are at 0 V or 5 V.

PARAMETER MEASUREMENT INFORMATION

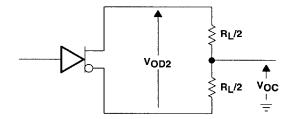
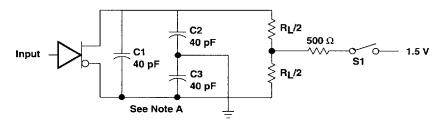
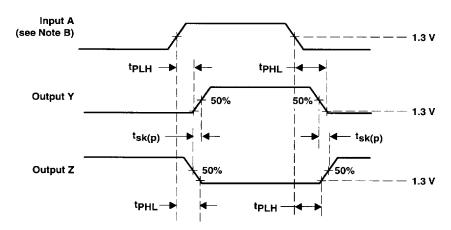


Figure 1. Differential and Common-Mode Output Voltages



TEST CIRCUIT



NOTES: A. C1 – C3 includes probe and jig capacitance.

B. All input pulses are supplied by generators having the following characteristics: PRR ≤ 1 MHz, duty cycle ≤ 50%, and t_f t_f ≤ 6 ns.

Figure 2. Propagation Delay Time and Skew Waveforms and Test Circuit

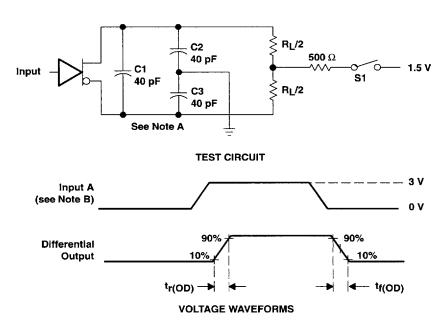


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PARAMETER MEASUREMENT INFORMATION



NOTES: A. C1 - C3 includes probe and jig capacitance.

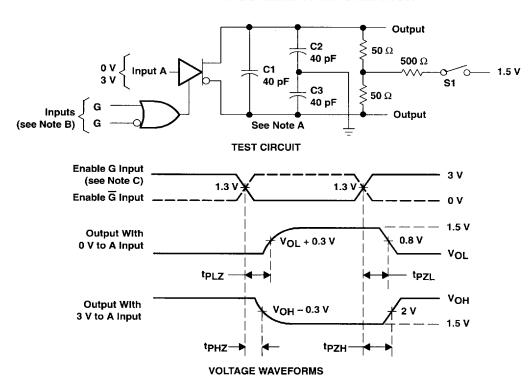
B. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, duty cycle \leq 50%, and t_r , $t_f \leq$ 6 ns.

Figure 3. Differential Output Rise and Fall Time Waveforms and Test Circuit



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PARAMETER MEASUREMENT INFORMATION



NOTES: A. C1 – C3 includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, duty cycle \leq 50%, t_r < 6 ns, and t_f < 6 ns.
- C. Each enable is tested separately.

Figure 4. Output Enable and Disable Time Waveforms and Test Circuit



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TYPICAL CHARACTERISTICS

SUPPLY CURRENT SWITCHING FREQUENCY 300 250

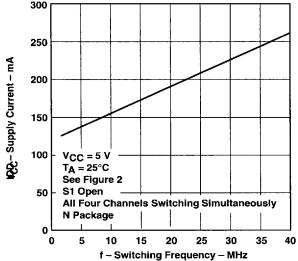


Figure 5

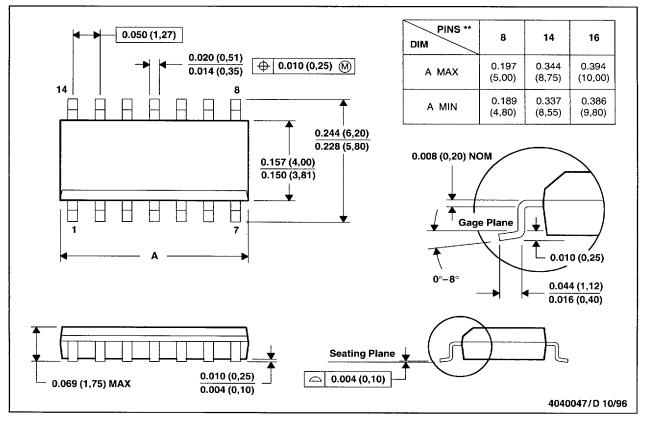
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MECHANICAL INFORMATION

D (R-PDSO-G**)

PLASTIC SMALL-OUTLINE PACKAGE

14 PIN SHOWN



NOTES: D. All linear dimensions are in inches (millimeters).

E. This drawing is subject to change without notice.

F. Body dimensions do not include mold flash or protrusion, not to exceed 0.006 (0,15).

G. Falls within JEDEC MS-012

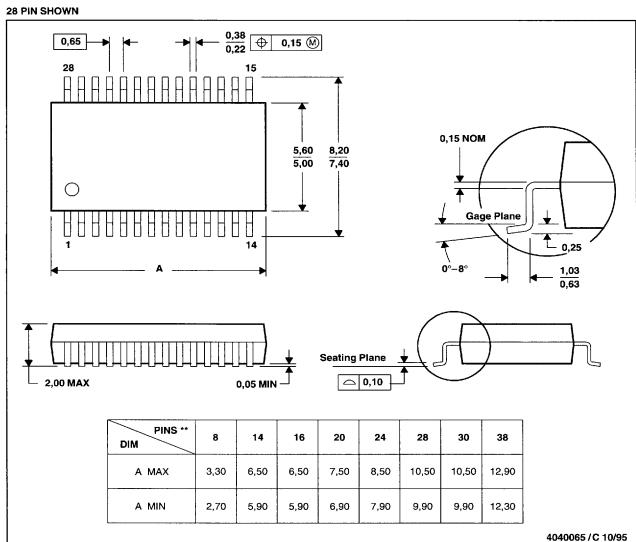


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MECHANICAL INFORMATION

DB (R-PDSO-G**)

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.
C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-150



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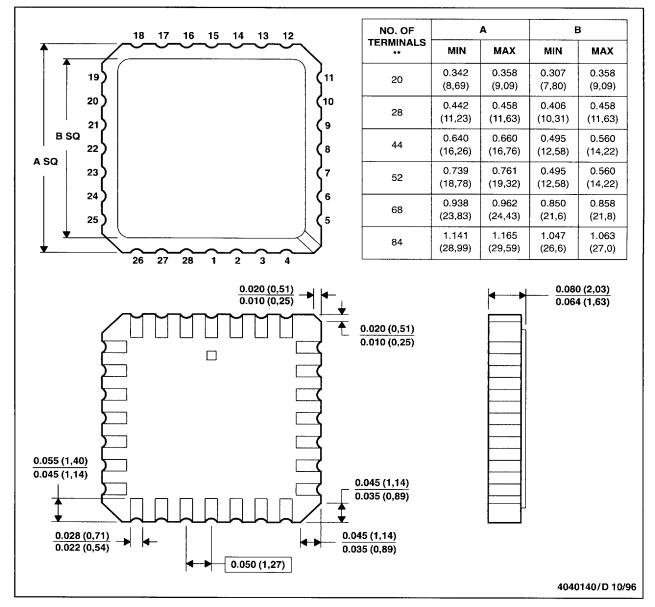
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MECHANICAL INFORMATION

FK (S-CQCC-N**)

28 TERMINAL SHOWN

LEADLESS CERAMIC CHIP CARRIER



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. This package can be hermetically sealed with a metal lid.
- D. The terminals are gold plated.
- E. Falls within JEDEC MS-004



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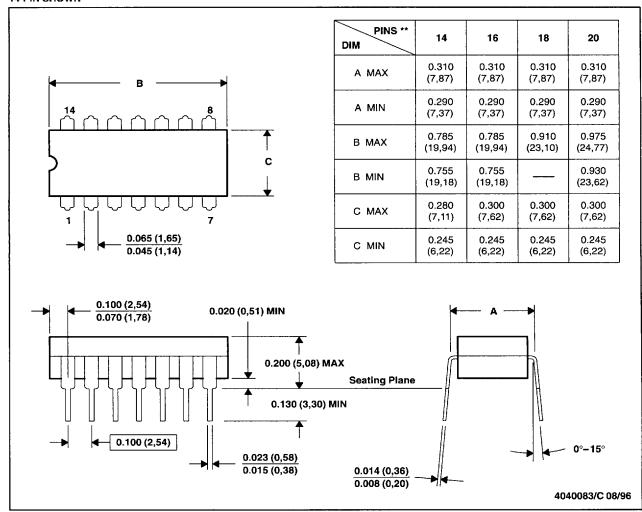
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MECHANICAL INFORMATION

J (R-GDIP-T**)

14 PIN SHOWN

CERAMIC DUAL-IN-LINE PACKAGE



- NOTES: A. All linear dimensions are in inches (millimeters).
 - B. This drawing is subject to change without notice.
 - C. This package can be hermetically sealed with a ceramic lid using glass frit.
 - D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
 - E. Falls within MIL-STD-1835 GDIP1-T14, GDIP1-T16, GDIP1-T18, and GDIP1-T20



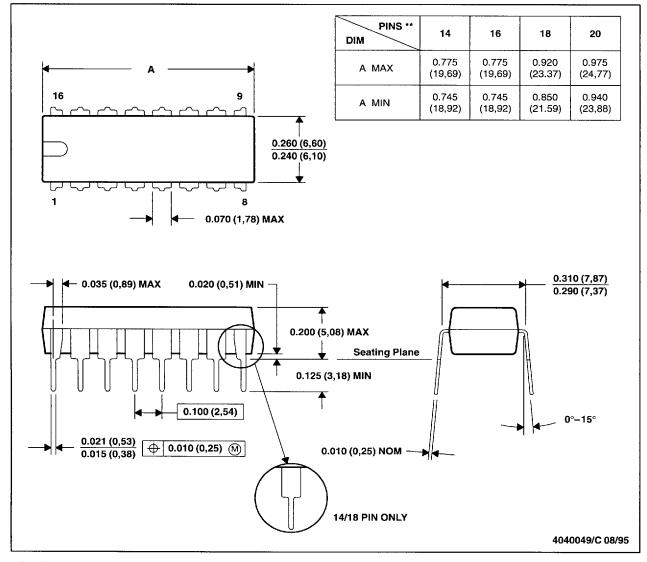
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MECHANICAL INFORMATION

N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PIN SHOWN



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

C. Falls within JEDEC MS-001 (20 pin package is shorter then MS-001.)

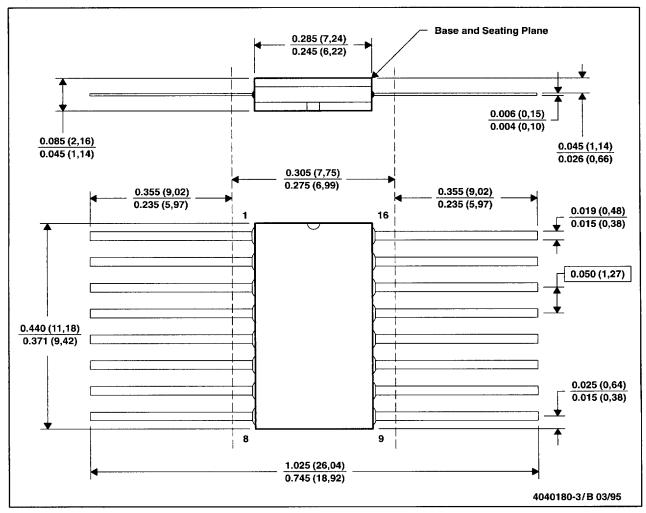


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MECHANICAL INFORMATION

W (R-GDFP-F16)

CERAMIC DUAL FLATPACK



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. This package can be hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only.
- E. Falls within MIL-STD-1835 GDFP1-F16 and JEDEC MO-092AC



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